

TOSHIBA Multichip Discrete Device

HN7G10FE

Power Management Switch Applications

Driver Circuit Applications

Interface Circuit Applications

- Q1 (transistor): 2SC5376F equivalent
- Q2 (MOSFET): SSM3K03FE equivalent

Q1 (transistor) Absolute Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Collector-base voltage	V _{CBO}	15	V
Collector-emitter voltage	V _{CEO}	12	V
Emitter-base voltage	V _{EBO}	5	V
Collector current	IC	400	mA
Base current	ΙΒ	50	mA

Q2 (MOSFET) Absolute Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Drain-source voltage	V _{DS}	20	V
Gate-source voltage	V _{GSS}	10	V
Drain current	ΙD	50	mA

Q1, Q2 Common Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Power dissipation	P _C (Note 1)	100	mW
Junction temperature	erature T _j 150		°C
Storage temperature range	T _{stg}	-55~150	°C

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

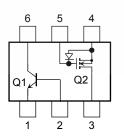
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: Total rating

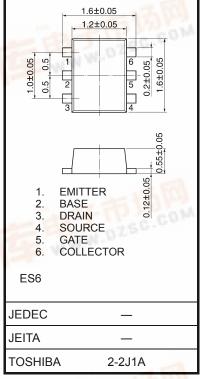
Note:

Marking Type Name h_{FE} Rank 78A

Pin Assignment (top view)



Unit: mm



Weight: 0.003 g (typ.)

Q1 (transistor) Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cutoff current	I _{CBO}	V _{CB} = 15 V, I _E = 0	_	_	0.1	μА
Emitter cutoff current	I _{EBO}	$V_{EB} = 5 \text{ V}, I_{C} = 0$	_	_	0.1	μА
DC current gain	h _{FE} (Note 2)	$V_{CE} = 2 \text{ V}, I_{C} = 10 \text{ mA}$	300	_	1000	
Collector-emitter saturation voltage	V _{CE} (sat) (1)	$I_C = 10 \text{ mA}, I_B = 0.5 \text{ mA}$	_	15	30	- mV
	V _{CE} (sat) (2)	$I_C = 200 \text{ mA}, I_B = 10 \text{ mA}$	_	110	250	
Base-emitter saturation voltage	V _{BE (sat)}	$I_C = 200 \text{ mA}, I_B = 10 \text{ mA}$		0.87	1.2	٧

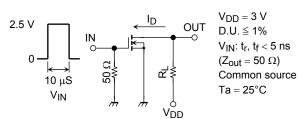
Note 2: hFE classification A: 300~600, B: 500~1000

Q2 (MOSFET) Electrical Characteristics (Ta = 25°C)

Characteristic Symb		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage curi	rent	I _{GSS}	V _{GS} = 10 V, V _{DS} = 0	_	_	1	μА
Drain-source brea	akdown voltage	V (BR) DSS	$I_D = 100 \ \mu A, \ V_{GS} = 0$	20	_	_	V
Drain cutoff curre	nt	I _{DSS}	$V_{DS} = 20 \text{ V}, V_{GS} = 0$	_	_	1	μА
Gate threshold vo	ltage	V _{th}	$V_{DS} = 3 \text{ V}, I_D = 0.1 \text{ mA}$	0.7	_	1.3	V
Forward transfer	admittance	Y _{fs}	$V_{DS} = 3 \text{ V}, I_D = 10 \text{ mA}$	25	50	_	mS
Drain-source ON-	resistance	R _{DS (ON)}	$I_D = 10 \text{ mA}, V_{GS} = 2.5 \text{ V}$	_	4	12	Ω
Input capacitance		C _{iss}	V _{DS} = 3 V, V _{GS} = 0, f = 1 MHz	_	11.0	_	pF
Reverse transfer	capacitance	C _{rss}	$V_{DS} = 3 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	3.3	_	pF
Output capacitance		Coss	$V_{DS} = 3 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	9.3	_	pF
Switching time	Turn-on time	t _{on}	$V_{DD} = 3 \text{ V}, I_D = 10 \text{ mA}, V_{GS} = 0~2.5 \text{ V}$	_	0.16	_	6
	Turn-off time	t _{off}	$V_{DD} = 3 \text{ V}, I_D = 10 \text{ mA}, V_{GS} = 0~2.5 \text{ V}$	_	0.19	_	μS

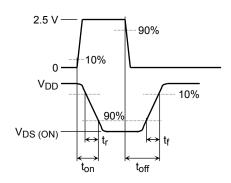
Switching Time Test Circuit

(a) Switching time test circuit

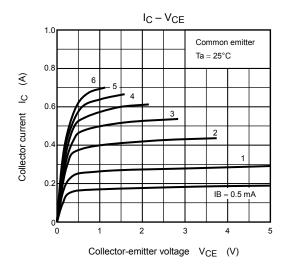


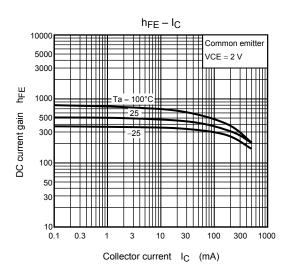
(b) V_{IN} V_{GS}

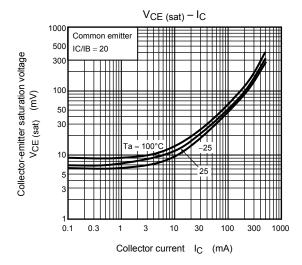
(c) V_{OUT} V_{DS}

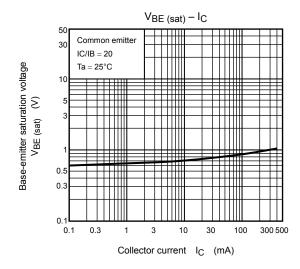


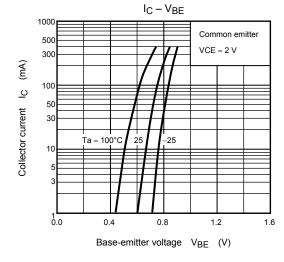
Q1 (Transistor)

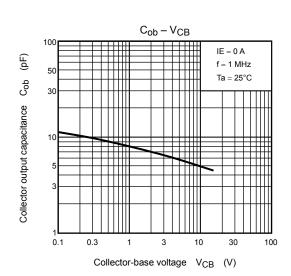




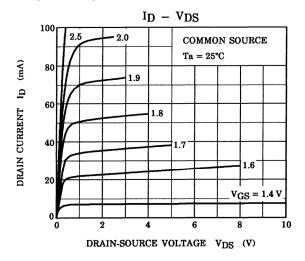


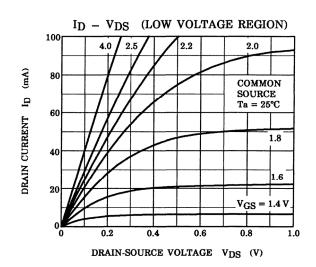


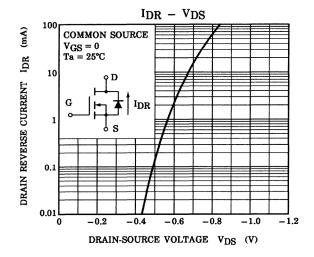


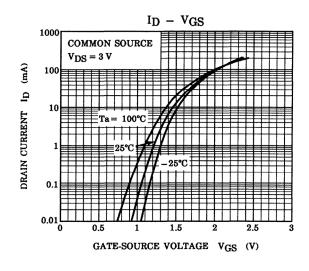


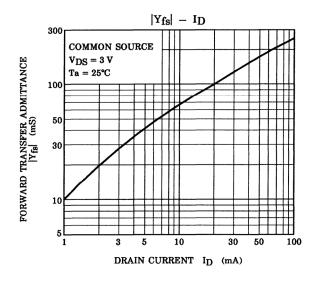
Q2 (S-MOS)

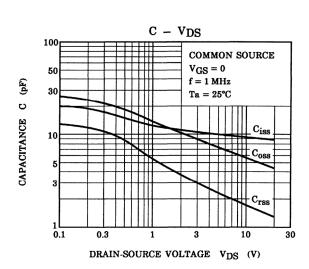




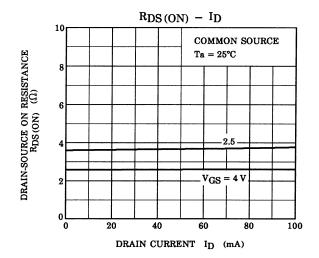


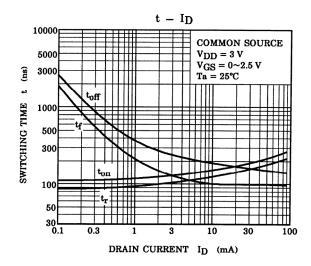


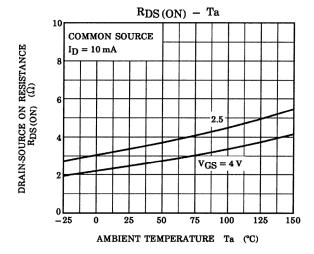




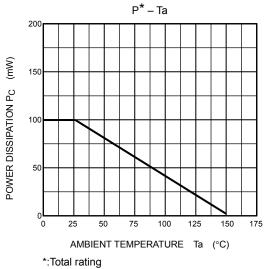
Q2 (S-MOS)







Q1, Q2 Common



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20070701-EN GENERAL

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